

Status of the MAPS project

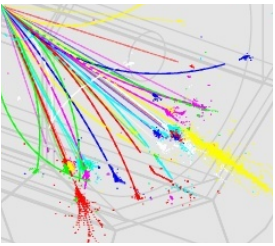
Imperial College 27.03.2007

Y. Mikami, O. Miller, V. Rajovic, N.K. Watson, J.A. Wilson
University of Birmingham

Mark Thomson
University of Cambridge

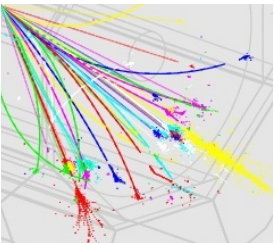
J.A. Ballin, P.D. Dauncey, A.-M. Magnan, M. Noy
Imperial College London

J.P. Crooks, M. Stanitzki, K.D. Stefanov, R. Turchetta, M. Tyndel, E.G. Villani
Rutherford Appleton Laboratory



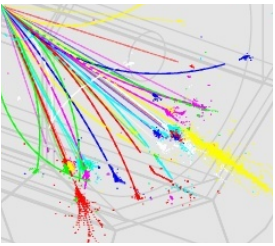
Overview

- Introduction
- Status
 - Sensor Design
 - Sensor Simulation
 - DAQ/Testing
 - Detector Simulations
- Next steps



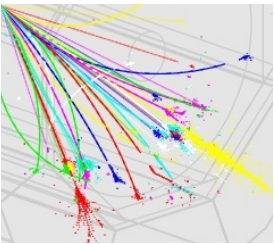
Introduction

- Development of an alternative readout sensor for the CALICE ECAL
- “Swap-In” Solution leaving mechanical structure untouched
- Use of MAPS with high granularity and digital readout

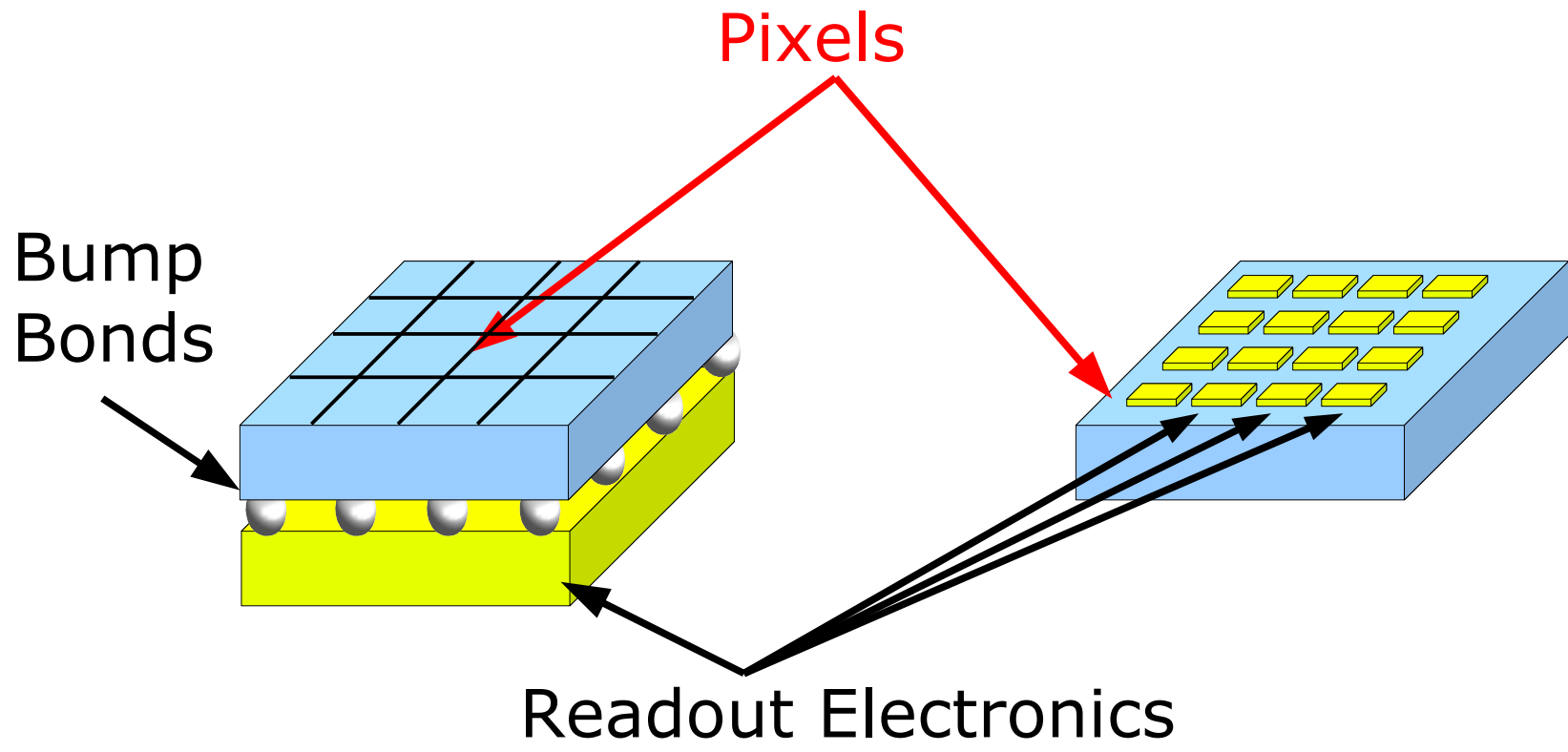


What are MAPS ?

- **M**onolithic **A**ctive **P**ixel **S**ensors
- Integration of Sensor and Readout Electronics
- Manufactured in Standard CMOS process
- Collects charge mainly by diffusion
- Development started in the mid-nineties, now a mature technology

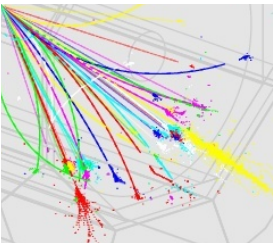


Hybrid Pixels and MAPS

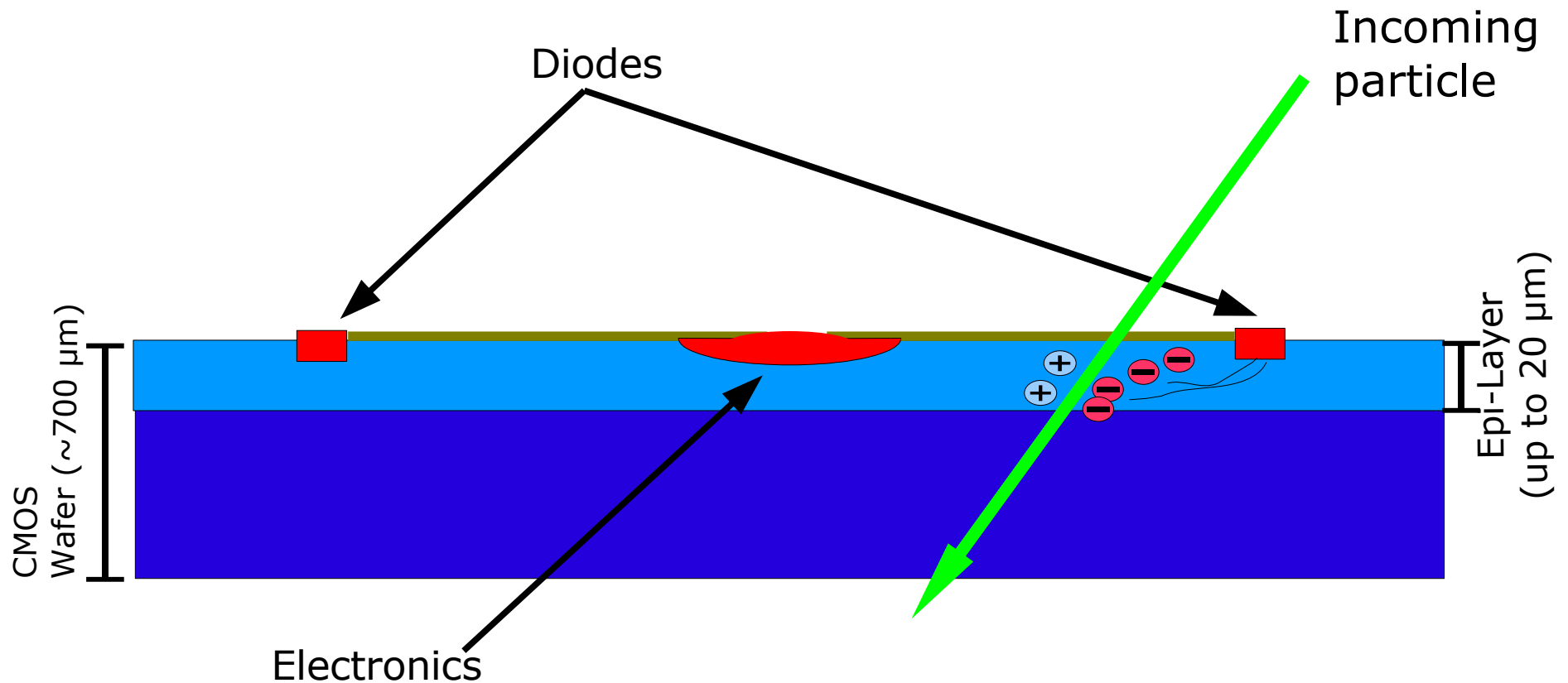


**LHC-style
Hybrid Pixel
sensor**

MAPS

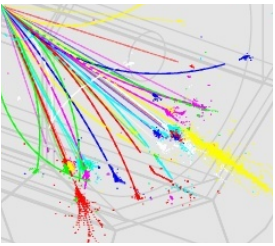


MAPS in Detail



MAPS architecture:

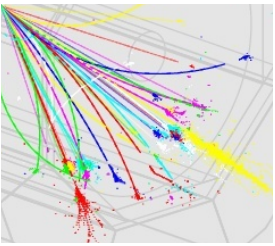
- Sensor and the electronics are integrated in one wafer
- Charge Collection mainly in epi-layer
- Charge collected mostly due to diffusion



The CALICE MAPS

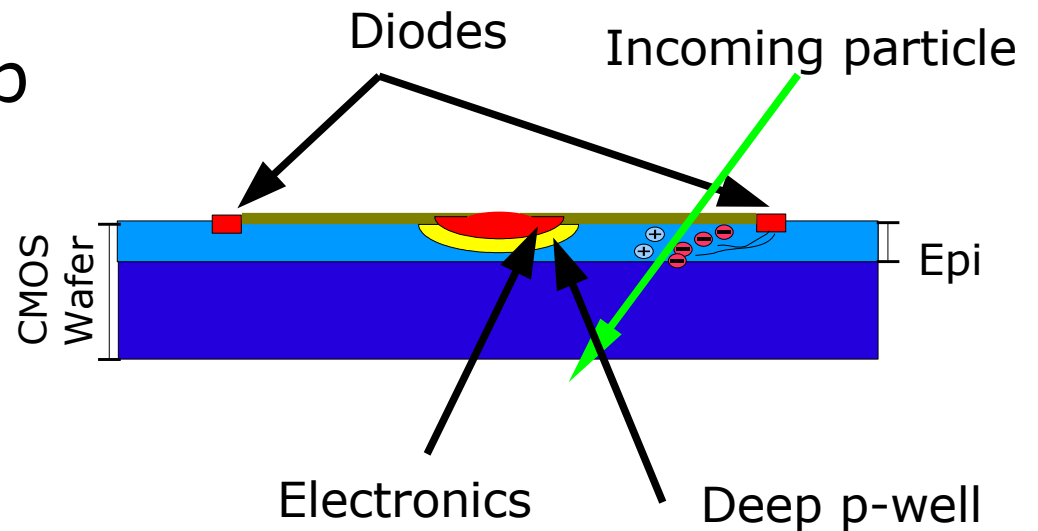
For the CALICE ECAL a specific MAPS was designed:

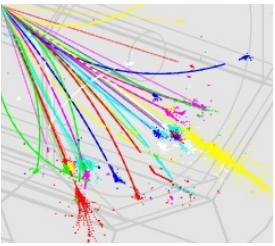
- Pixel Size (50 x 50 μ)
- Binary Readout (1 bit ADC realized as Comparator)
- 4 Diodes for Charge Collection
- 13 bit Time Stamping
- Hit buffering for entire bunch train
- Capability to mask individual pixels
- Threshold adjustment for each pixel



A new process technology

- Simulation showed, that the n-wells absorb a lot of charge (hence affecting the signal)
- We isolated the n-well with a “deep p-well” implant (3 μm thick)
- Novel *INMAPS* process used for the CALICE MAPS



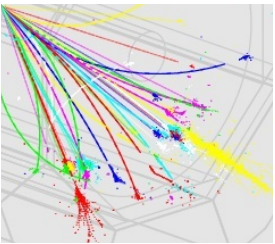


Sensor Electronics

- Two types of pixel readout
- Shaper & Sample

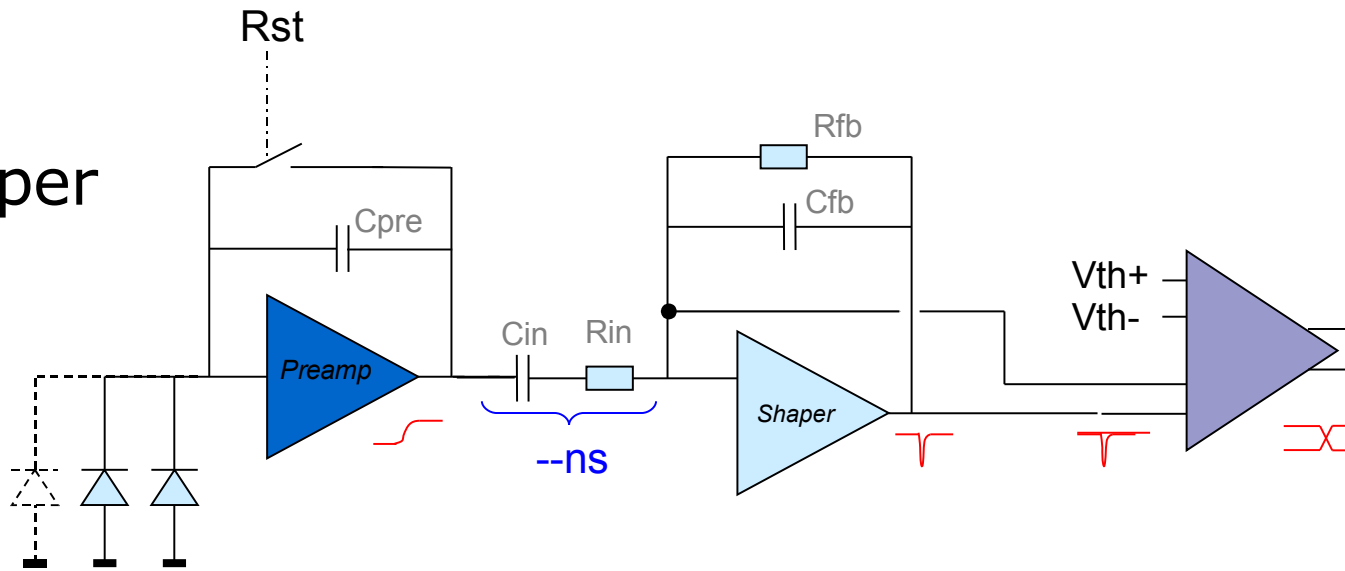
	<i>Pre-Shaper</i>	<i>Pre-Sampler</i>
Deadtime	Varies with Signal	Constant
Reset	Self-resetting	Active reset
Diode mode	Current	Voltage

- Average deadtime (~ 600 ns/ 450 ns)
- Simulation shows similar noise characteristics
- Both share the Comparator design
- Having two readout architectures allows us to explore several ideas at once

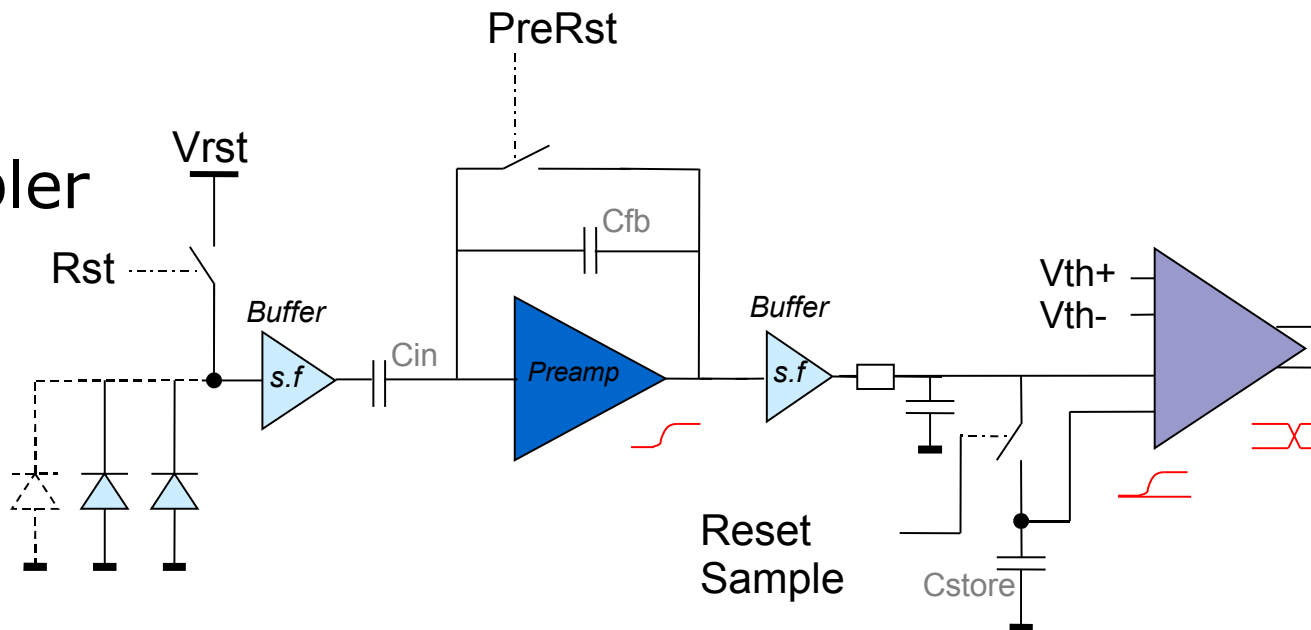


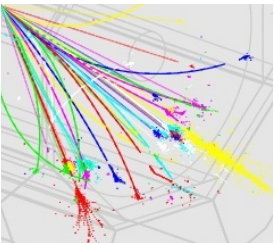
The two pixels

Pre-Shaper



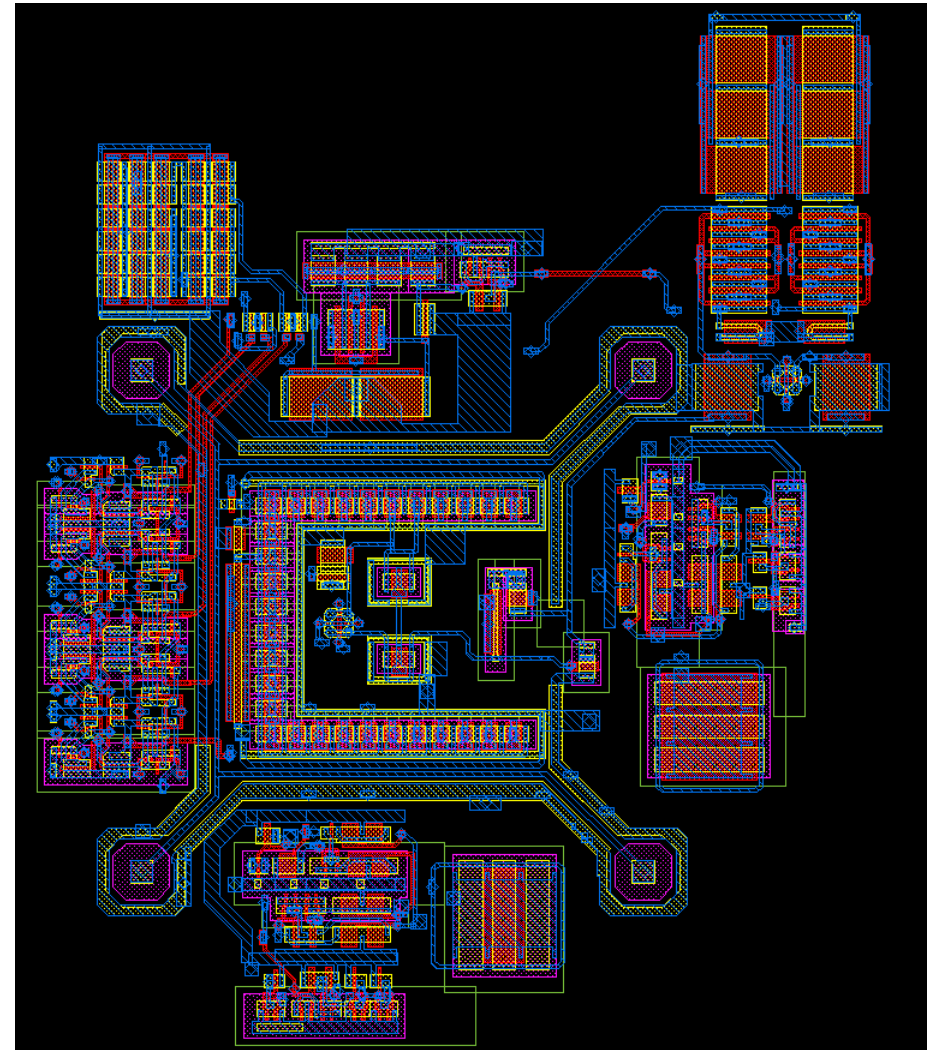
Pre-Sampler

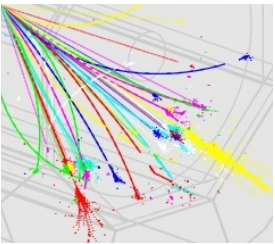




The Pixel

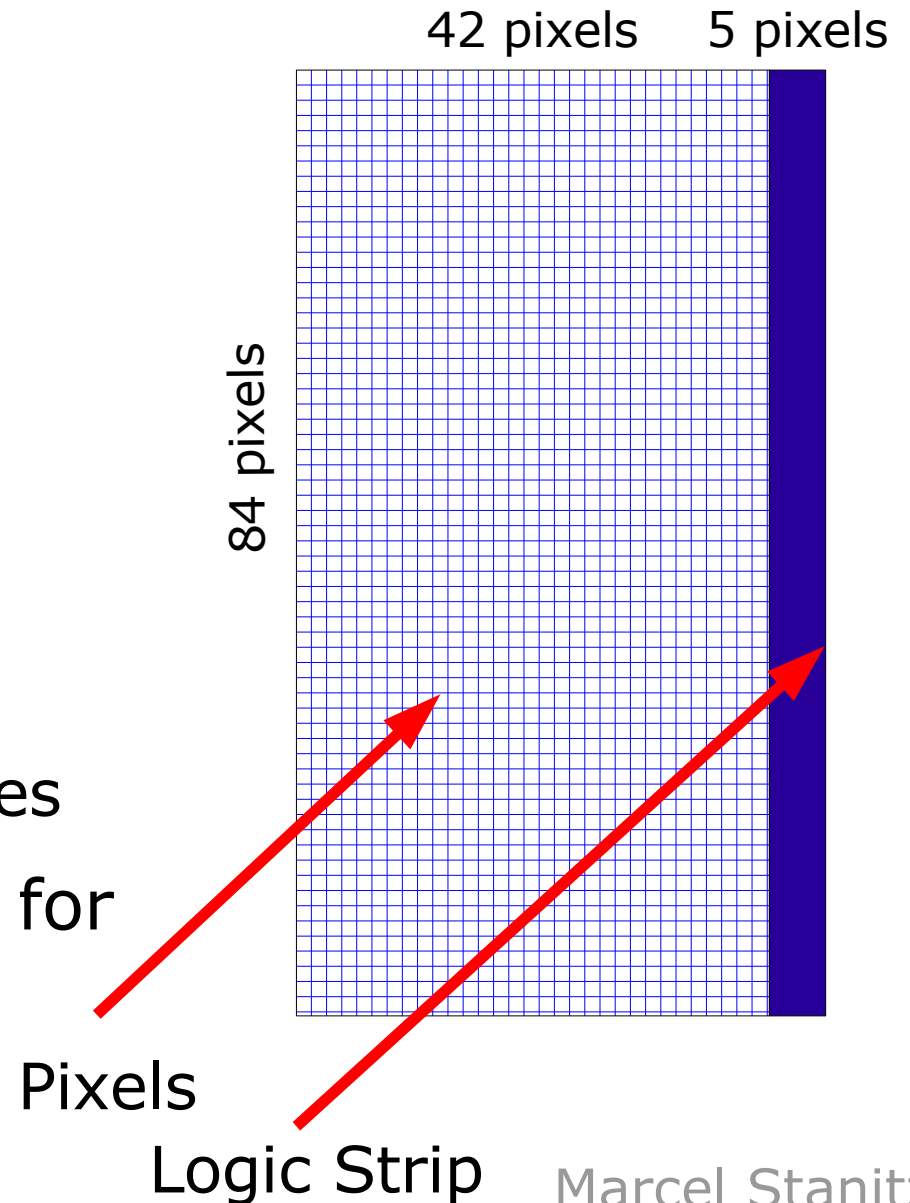
- 50x50 μm size
- 0.18 μm process
- 12 μm Epi-layer
- Deep p-wells
- 5 metal layers
- 224 1.8 V transistors
- 1 3.3 V transistor
- 36 capacitors

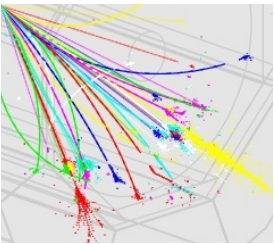




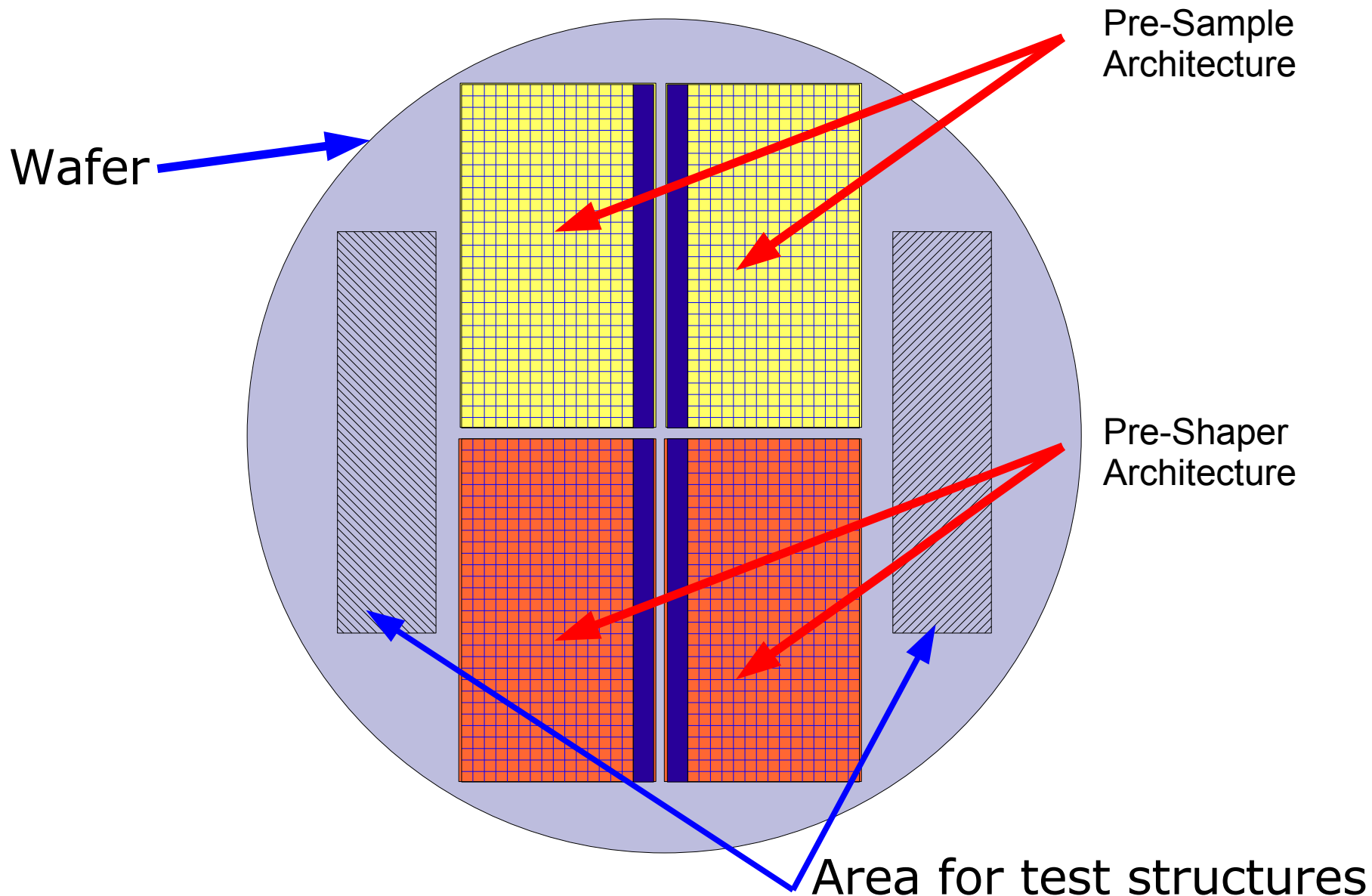
The test sensor (V1.0)

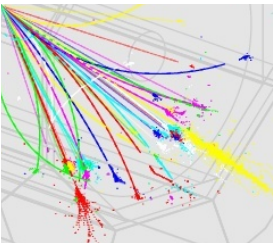
- Consists of 42x84 pixels
- Has a logic strip for
 - 5 pixels wide
 - Hit buffering using SRAM technology
 - Time stamping (13 bit)
 - Configuration registers
 - the only part with Clock lines
- Logic strip is a “dead area” for particle detection (~ 11 % inefficiency)





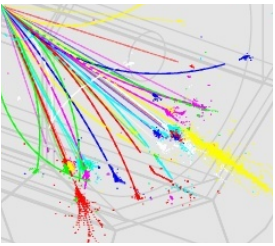
The test structure (V1.0)





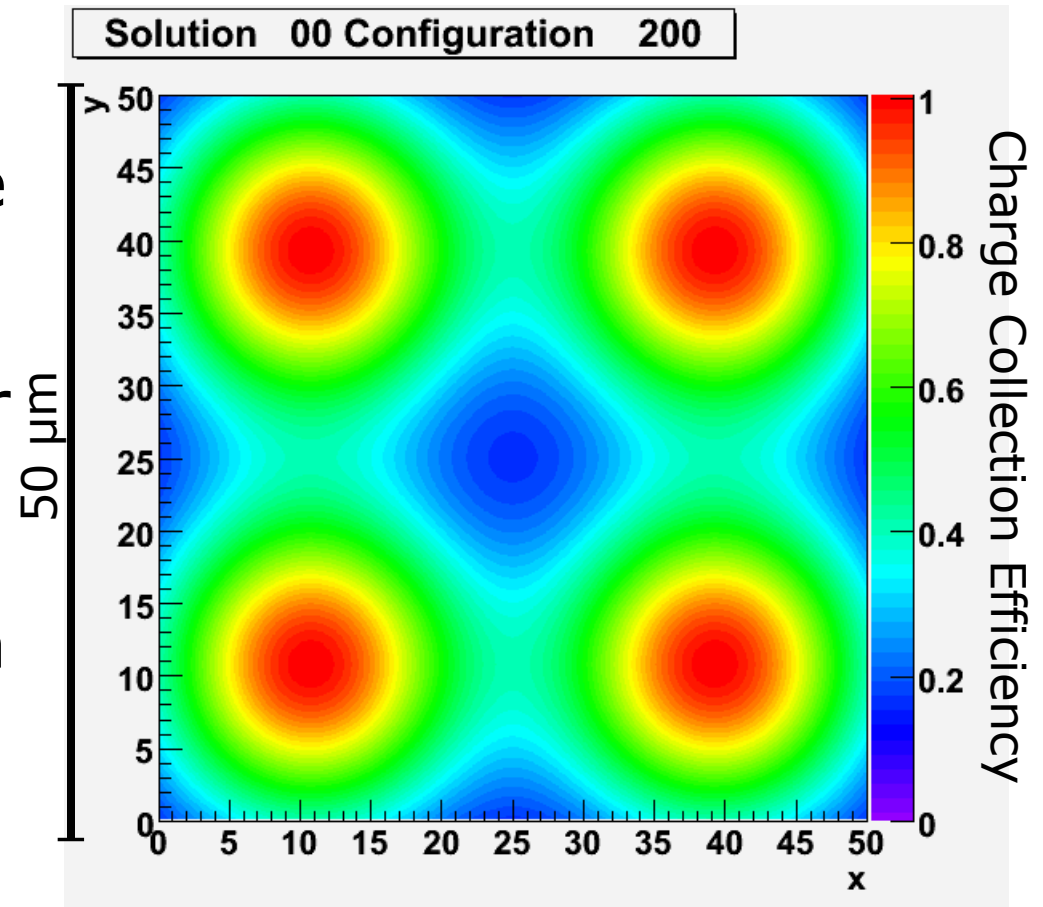
Sensor Simulation

- We are using Centaurus TCAD to simulate the sensor
- Using CADENCE GDS file for pixel description
- Simulate diodes from adjacent pixels for charge sharing effects
- Detailed Pixel performance studies
 - Collection Efficiency
 - Charge Collection Time
 - Signal/Noise



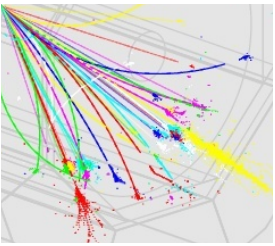
Diode placement

- Classical problem
 - Place n circles in a square
 - No analytical solution
- Only 4 Diodes as a starter
- Mathematics faces reality
 - Constraints due to Design Rules
 - Electronics
 - Space



Numerical Solution

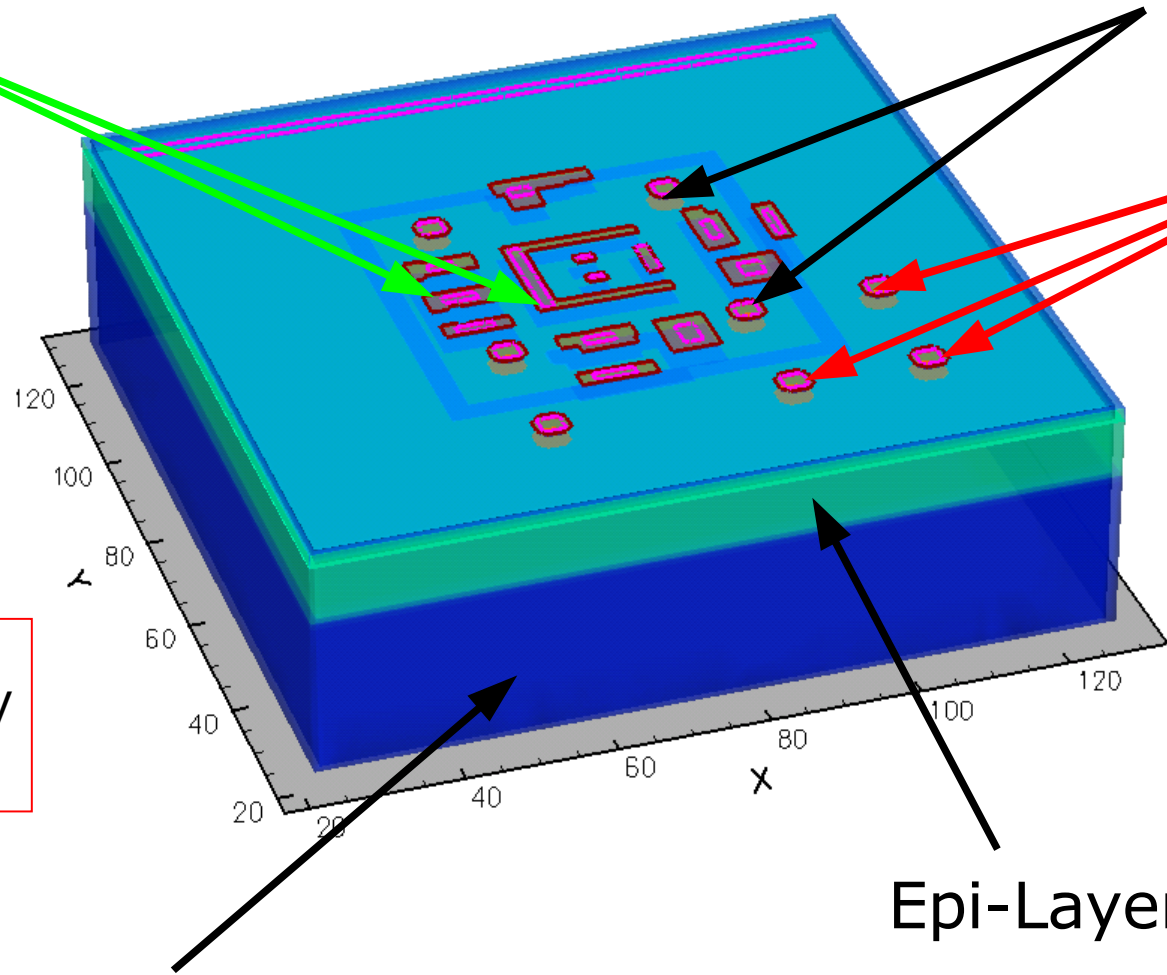
The setup



Electronics

Diodes

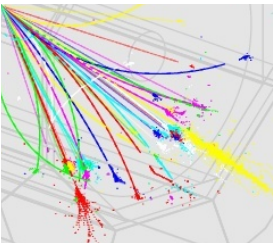
Adjacent
Diodes



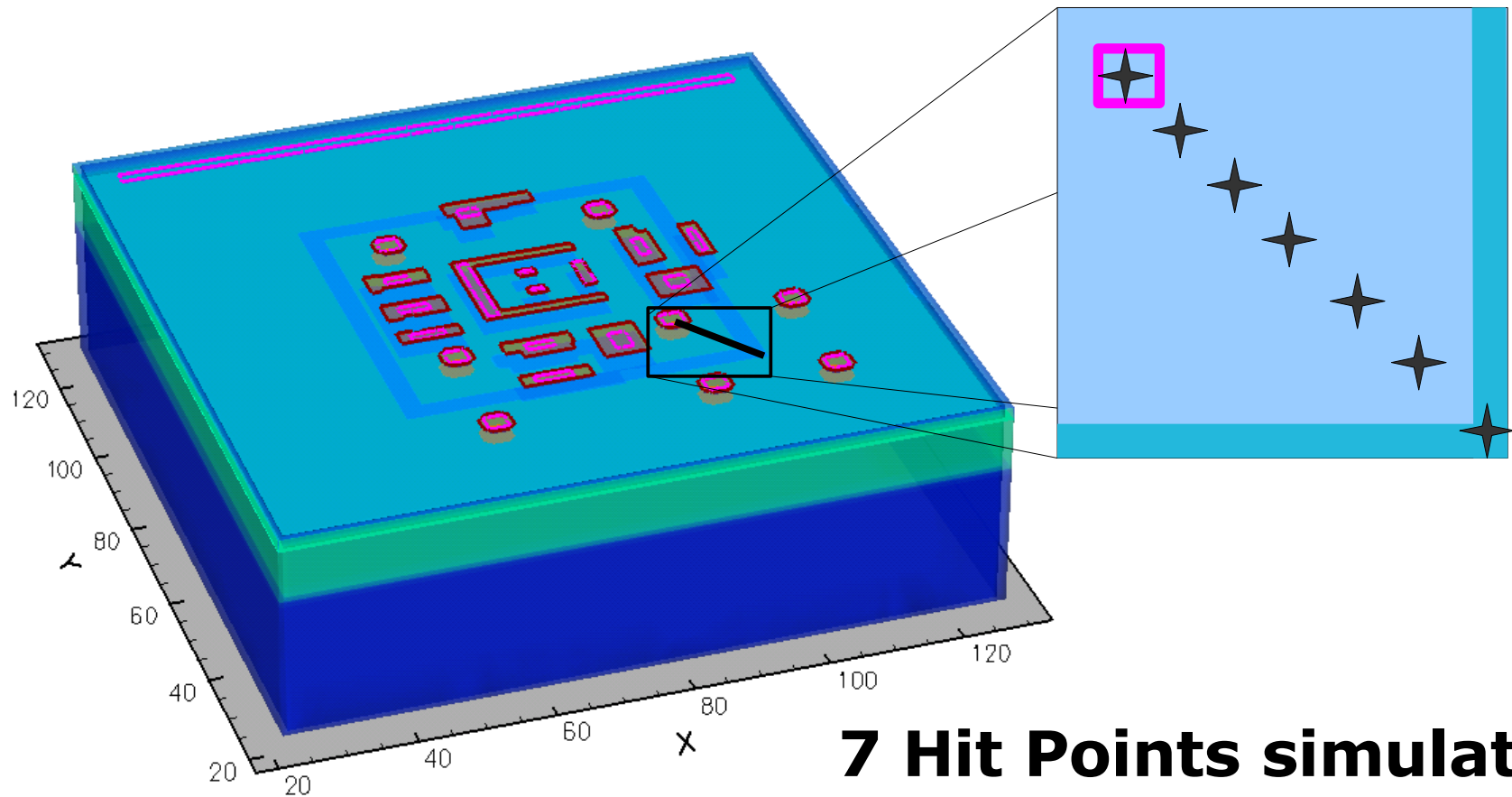
Bias:
•n-Well 1.8/1V
•Diodes: 1.5V

Substrate

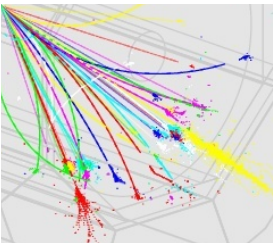
Epi-Layer



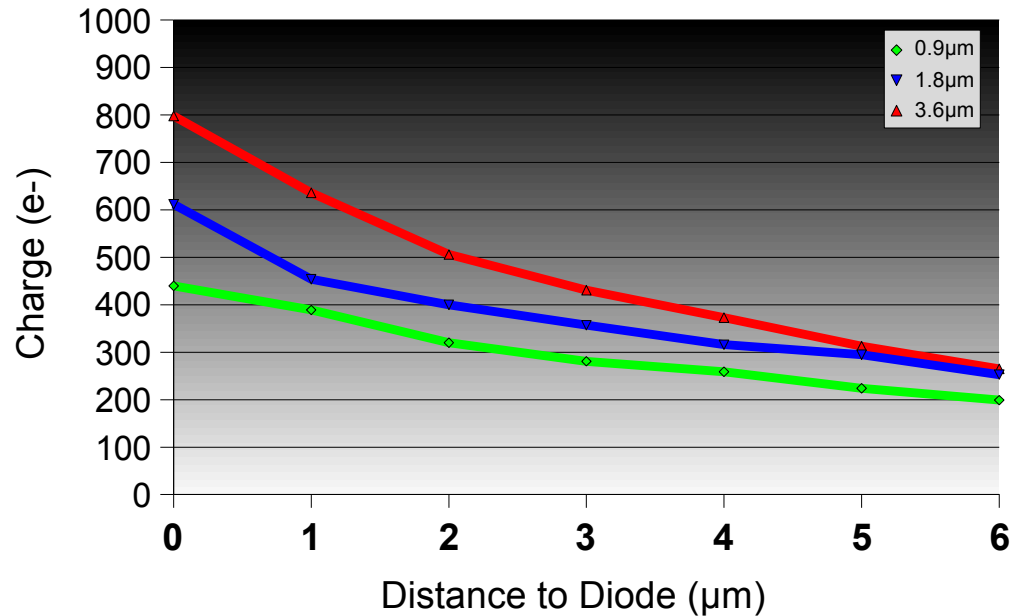
Simulation Setup



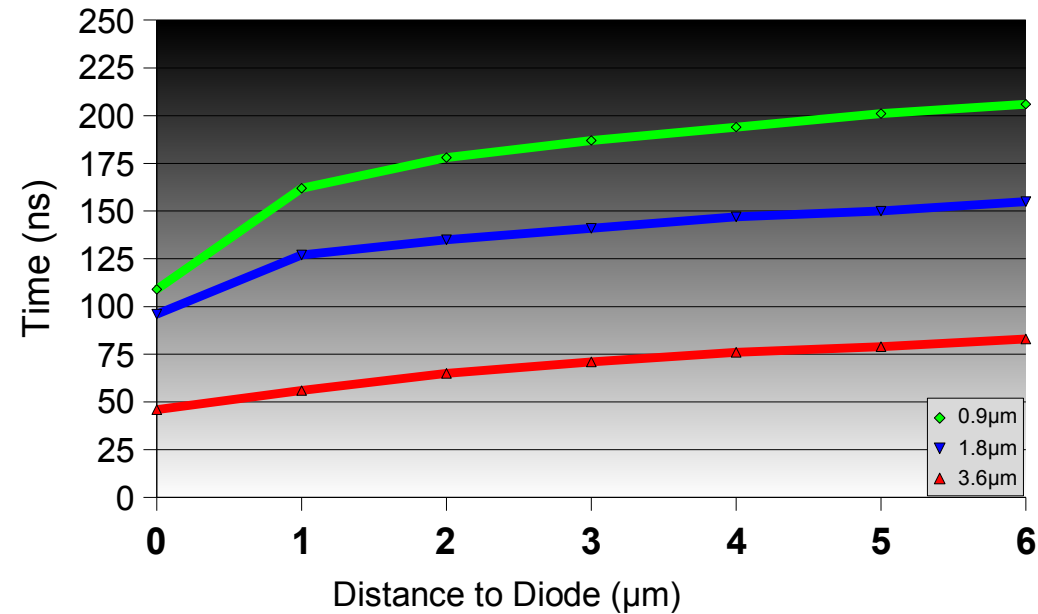
Charge Collection



Charge collected

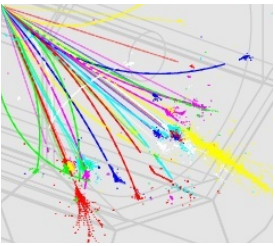


Collection Time



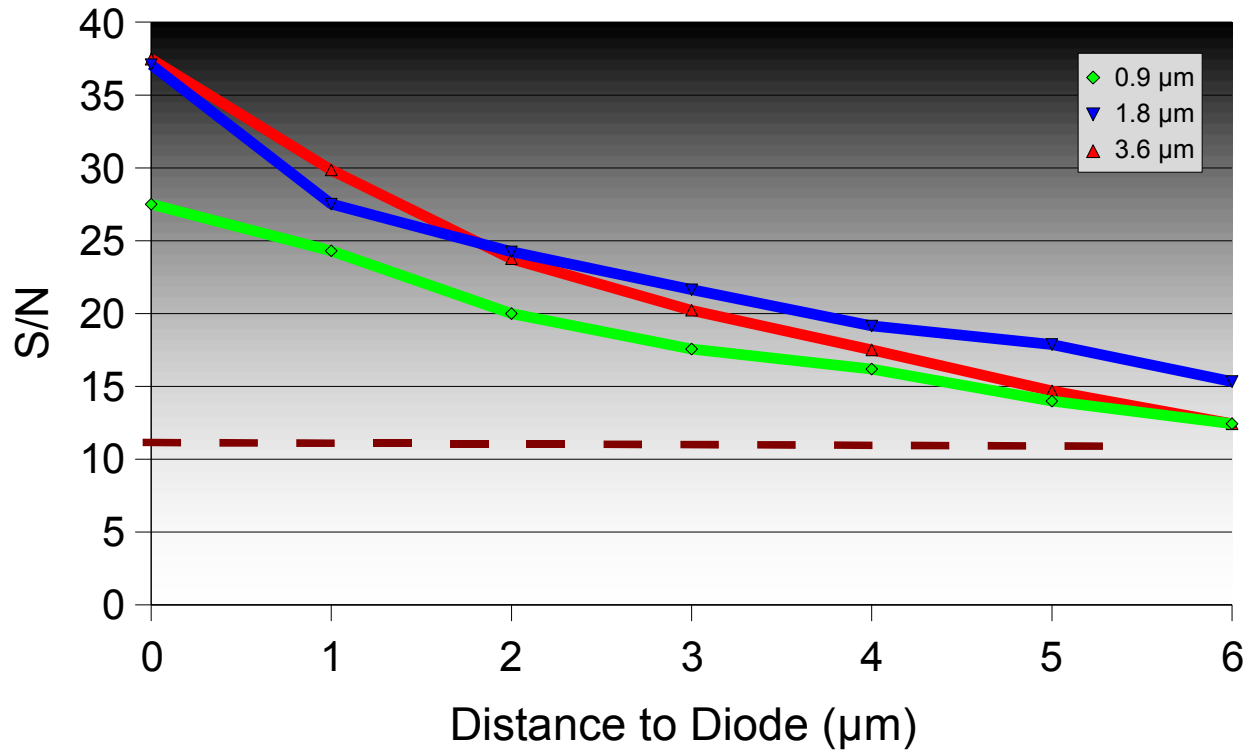
Main parameter to vary is Diode Size

ILC Bunch spacing ~ 300 ns



Signal/Noise

Signal/Noise

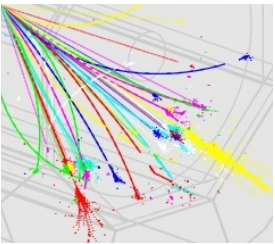


*N.B. S/N 0.9μm N = 16 e⁻

*N.B. S/N 1.8μm N = 16.5 e⁻

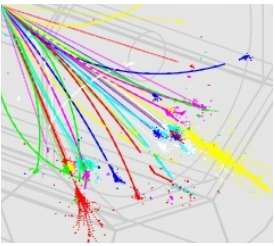
*N.B. S/N 3.6μm N = 21.3 e⁻

Signal to Noise > 15 for 1.8 μm Diode Size



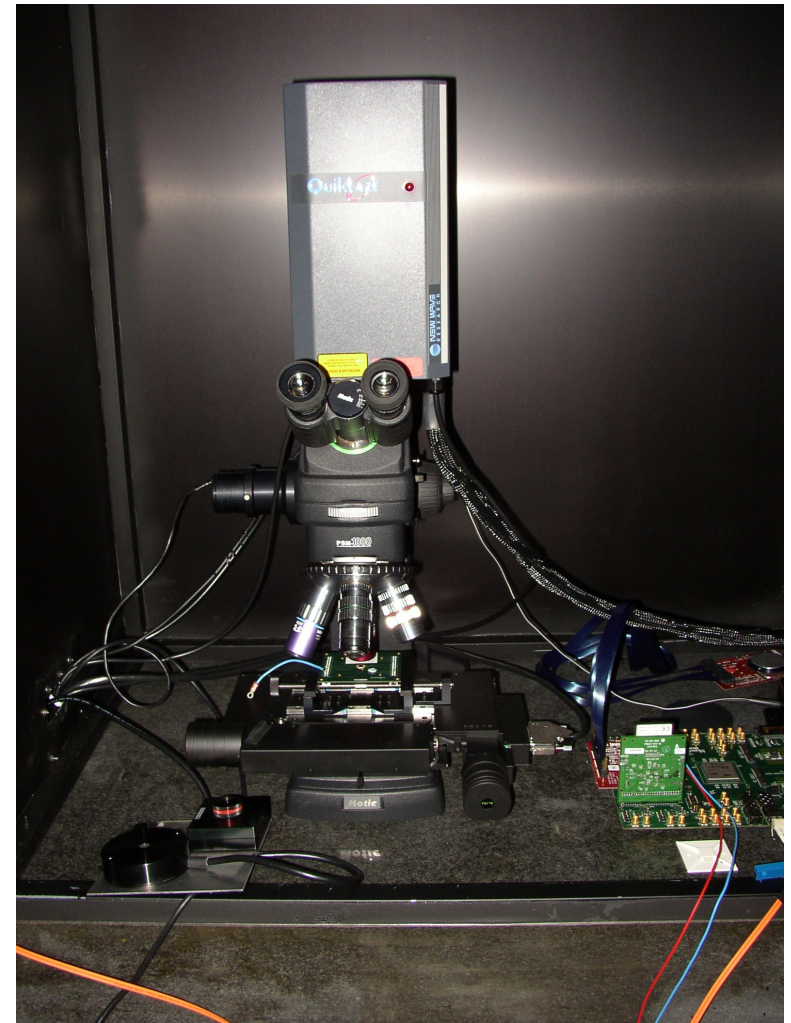
MAPS DAQ & Testing

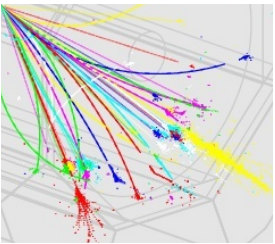
- Development of DAQ board and firmware has started
- Complete test setup foreseen
 - Cosmics
 - Sources
 - Laser
 - Test beam



RAL Laser Test setup

- Powerful Laser setup
- 1064, 532 and 355 nm Wavelength
- Accurate focusing ($<2 \mu\text{m}$)
- 50 Hz Repetition rate
- Fully automatized
- Will be used to test the CALICE MAPS

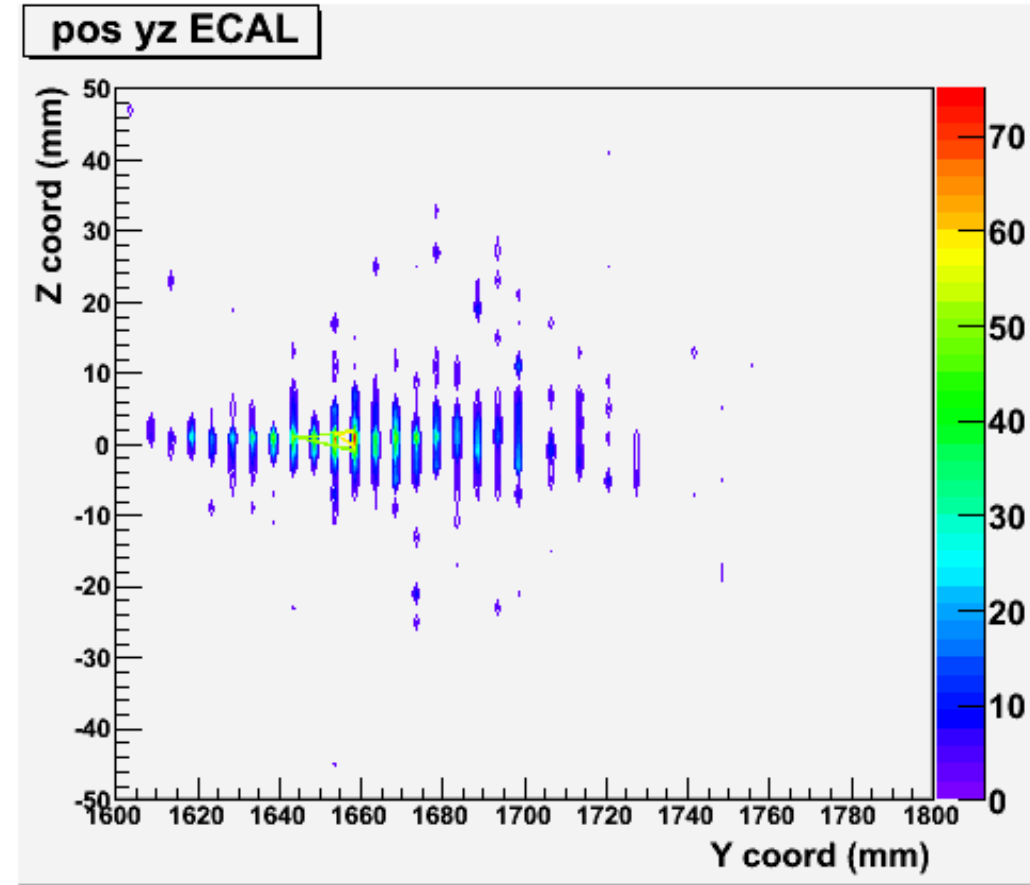
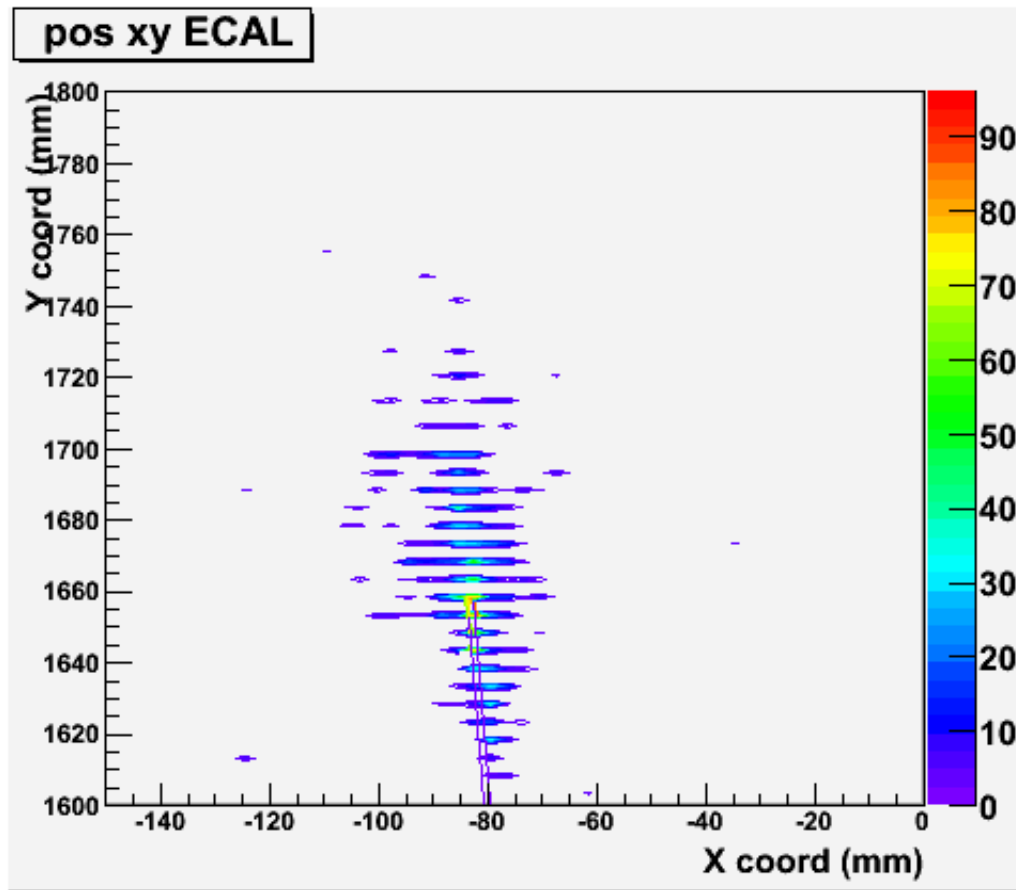
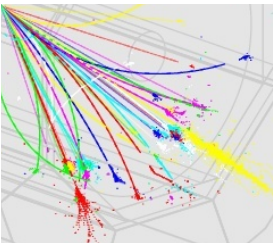




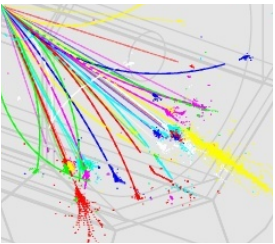
Detector Simulation

- Implementation of the MAPS into GEANT/MOKKA
 - Patched MOKKA 6.02
- 50x50 μm pixel size
- 15 μm “Active Area” (Epi-layer)
- Detector Model used LDC01(Sc)
- ECAL with 30 layers
 - 20 layers 2.1 mm Tungsten
 - 10 layers 4.2 mm Tungsten
- Charge diffusion and thresholds are implemented in a separate “Digitization” step

Shower Shapes

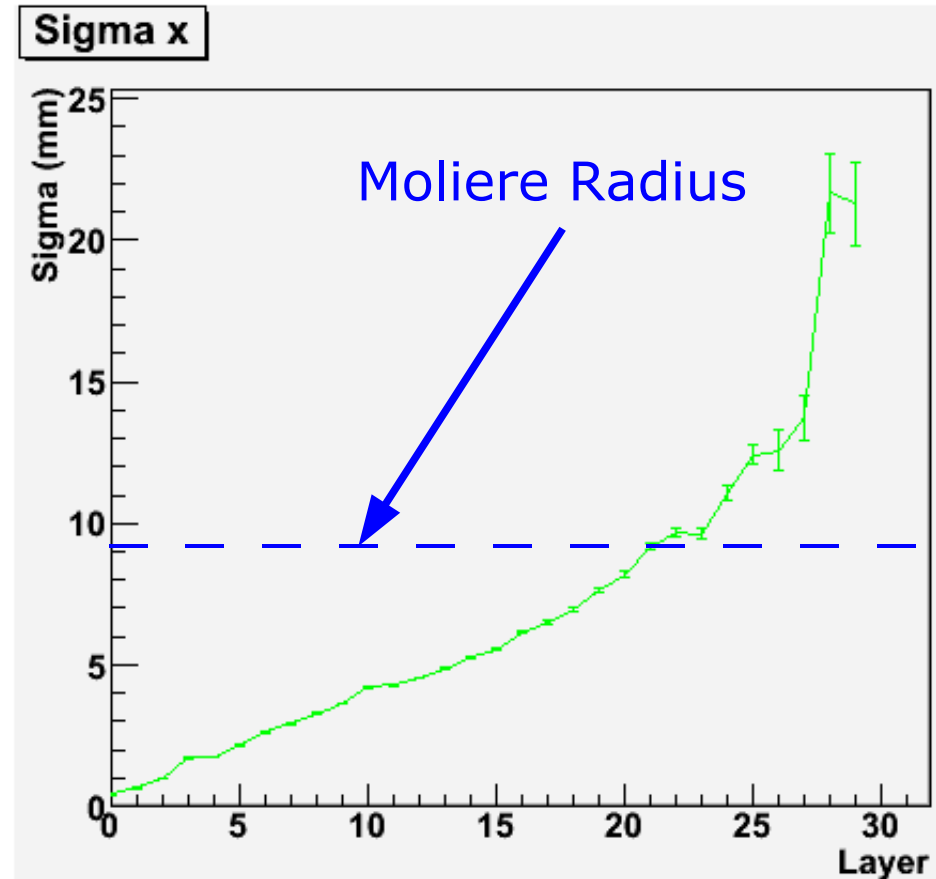
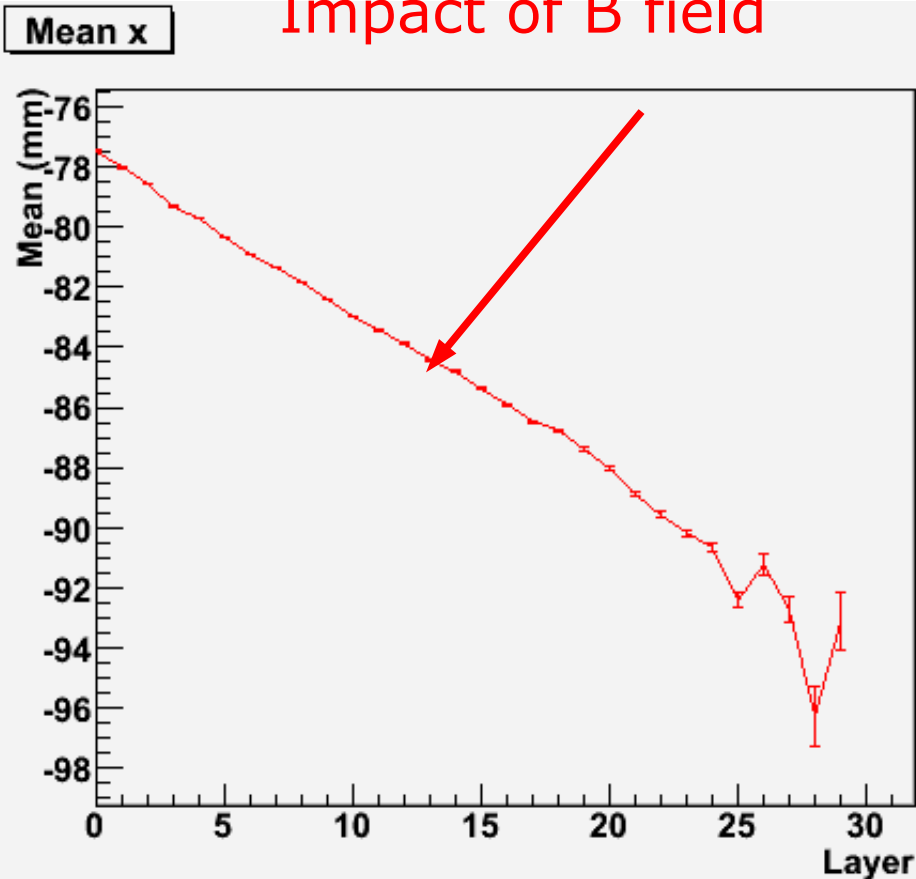


GEANT4 : One 20 GeV Electron shot along y-axis

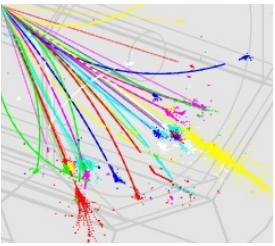


Spatial resolution in x

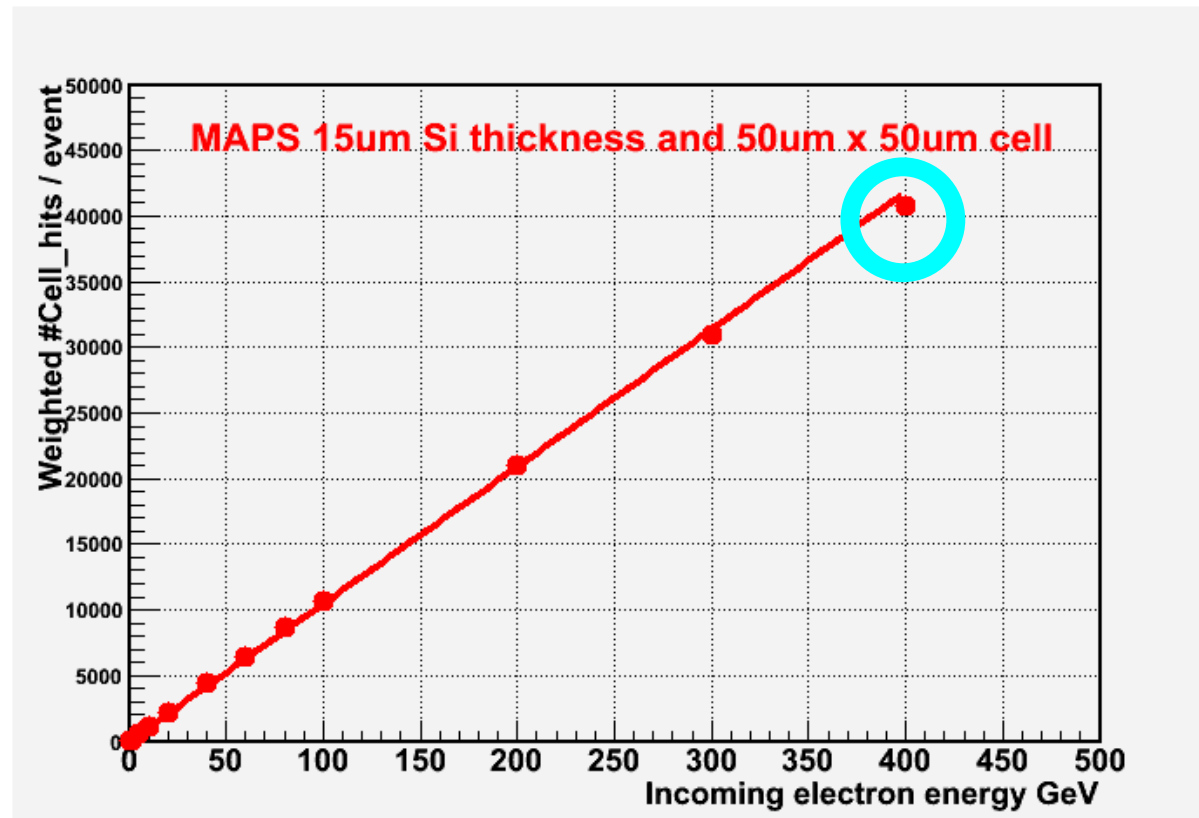
Impact of B field



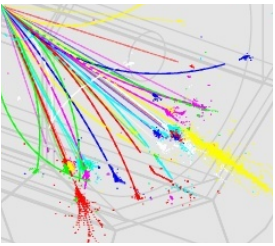
GEANT4 :20 GeV Electrons shot along y-axis



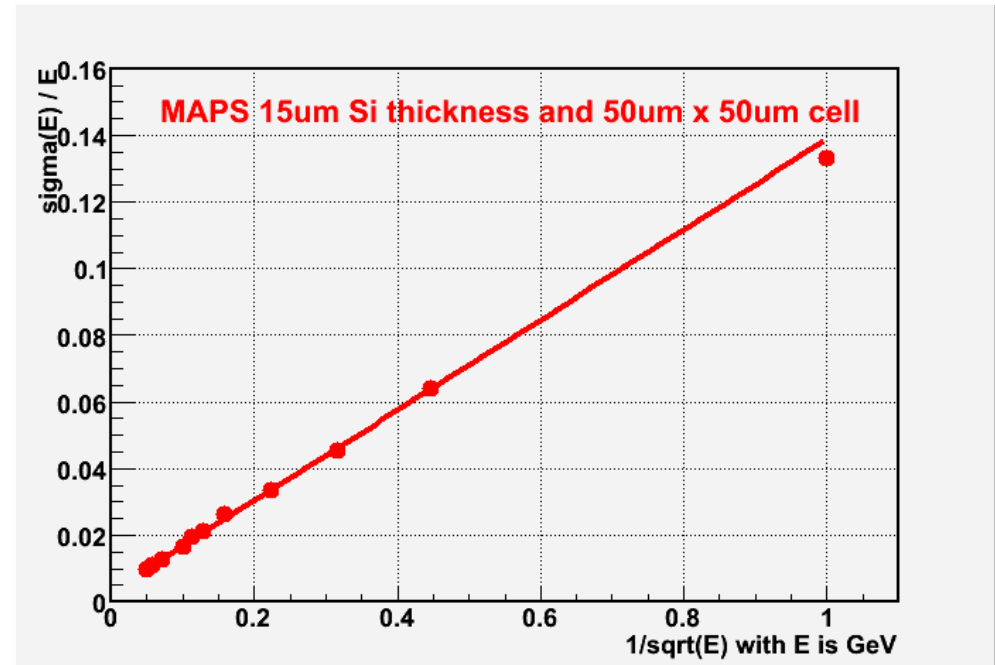
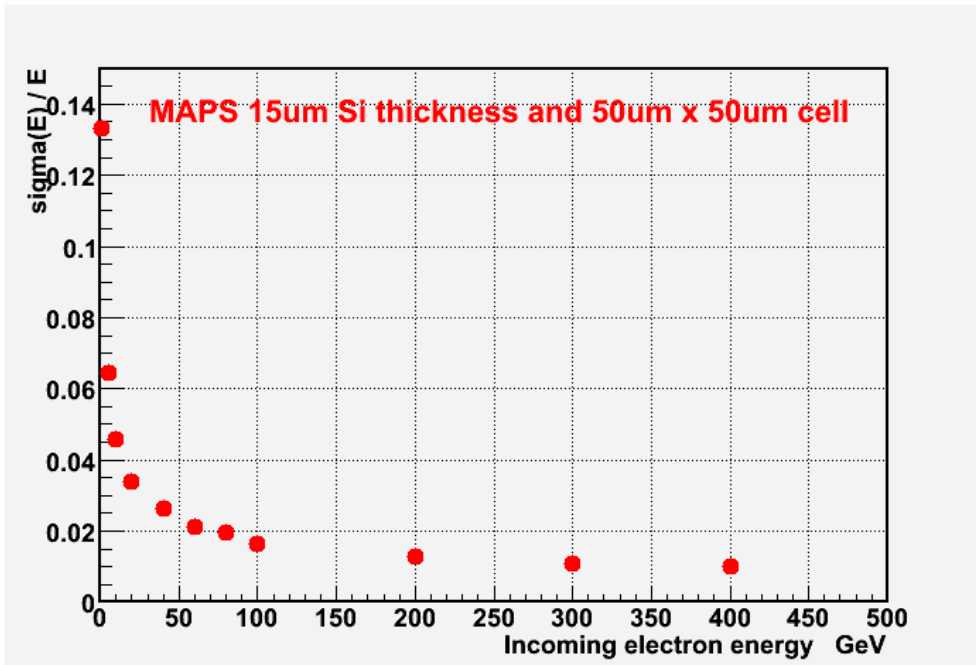
Linear Response



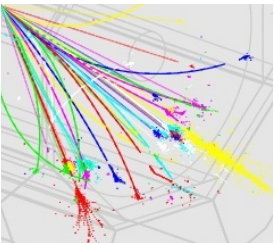
Linear response for electrons up to 400 GeV
GEANT4 level without charge diffusion



Resolution

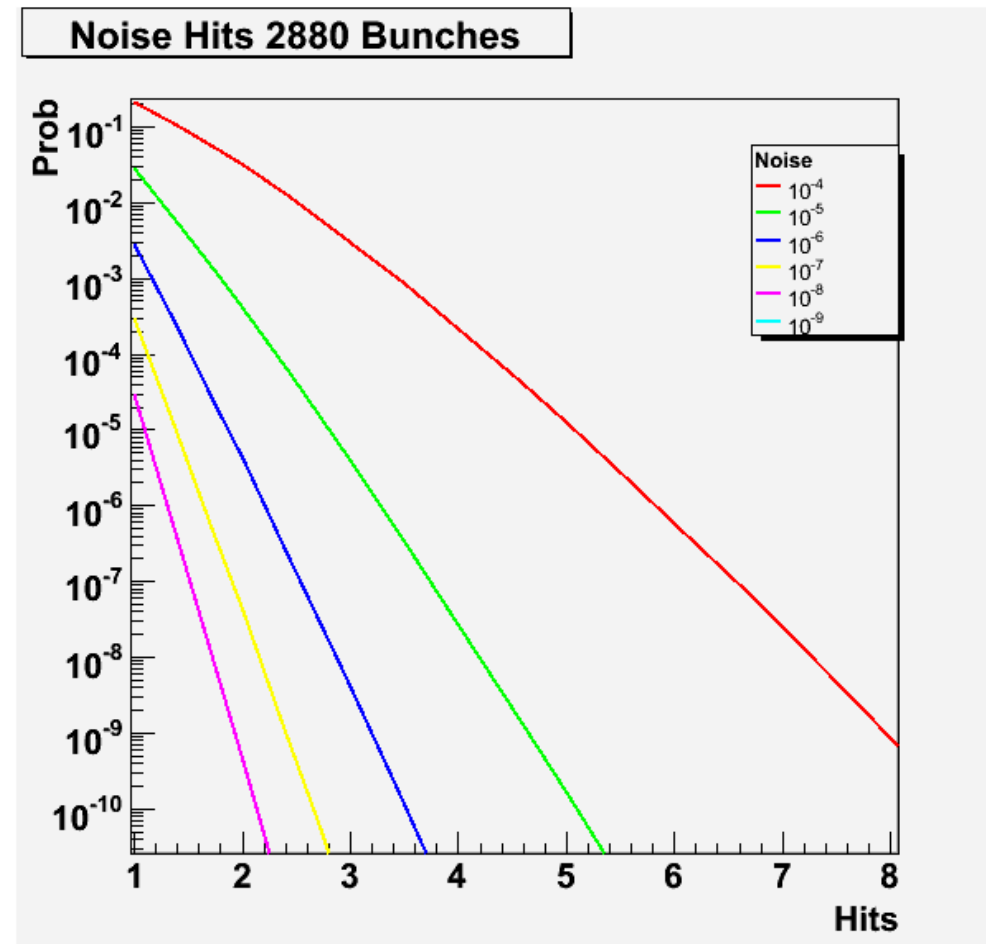


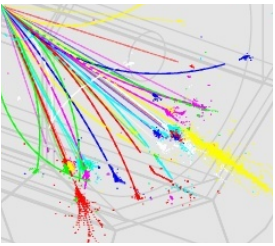
Good resolution over wide energy range
GEANT4 level without charge diffusion



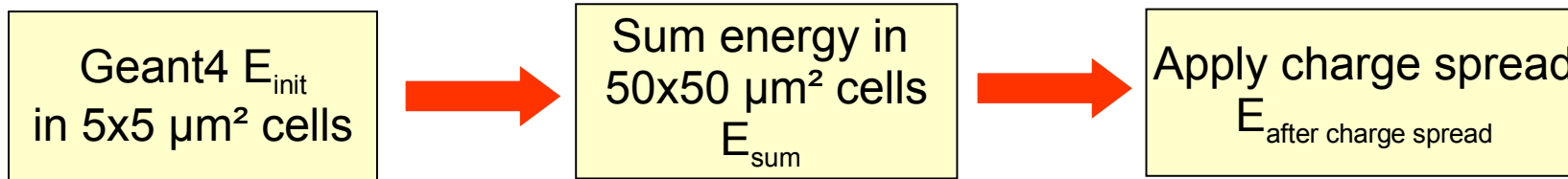
Noise Occupancy

- Noise for 2880 bunches
- Vary noise probability
- With Noise= $O(10^{-6})$
 - P=0.3 % for 1 hit per pixel
 - P=0.0004 % for 2 hit per pixel
- But $O(10^{12})$ pixels !
 - $\sim 3 \cdot 10^9$ single hits
 - $\sim 4 \cdot 10^6$ double hits
 - ~ 0 triple hits





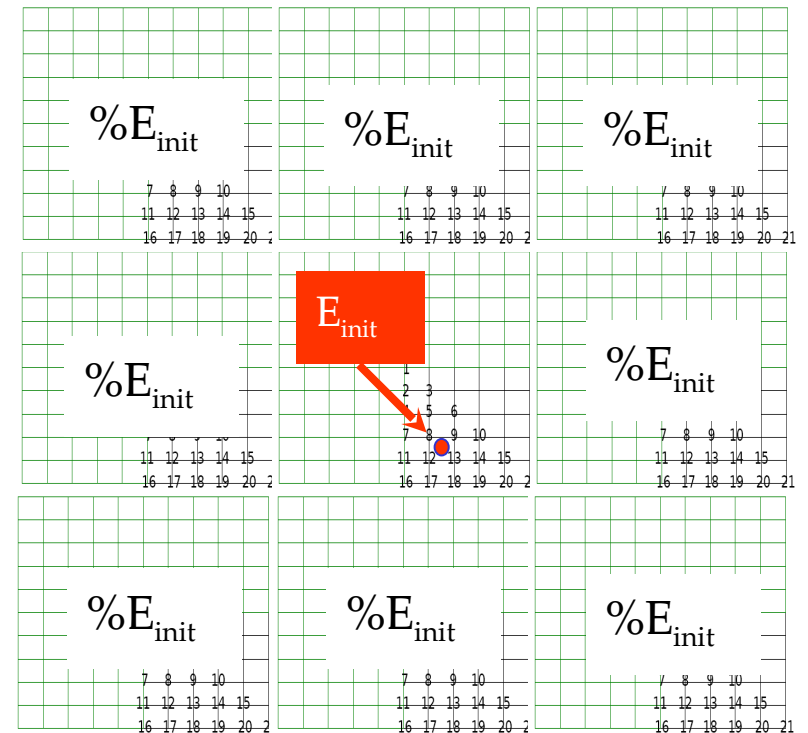
Charge sharing algorithm



Add noise to signal hits
with $\sigma = 90$ eV
(1 e⁻ ~ 3 eV 30e⁻ noise)

+ noise only hits
prob. $10^{-6} \rightarrow \sim 10^6$ hits in the whole detector
BUT in
a 1 cm² tower : ~30 hits in 30 layers.

Register the position and the number
of hits above threshold

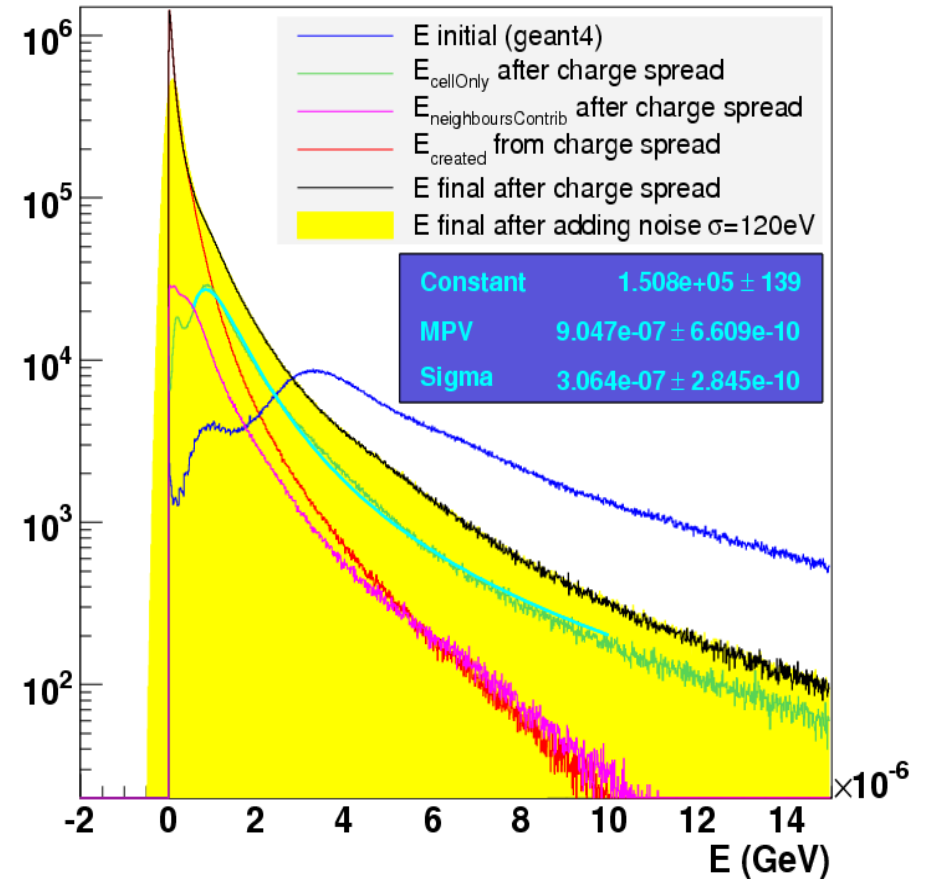


$$\sum E_{neighbours} \sim (50\% - 80\%) \times E_{init}$$

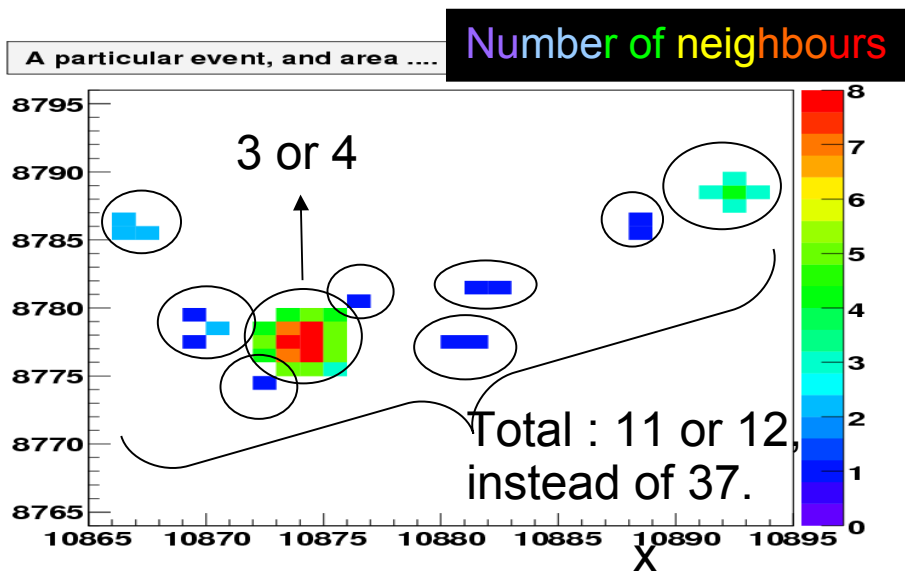
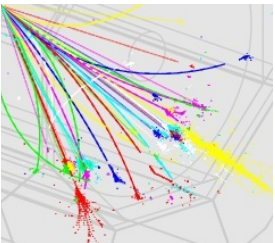
First results

- Algorithm depends on accurate simulation input from Centaurus
- First results shows algorithm work nicely
- Does not take into account deep p-well yet
- Will be updated with the latest pixel simulations and noise estimates

200 GeV e, diode 1.8um



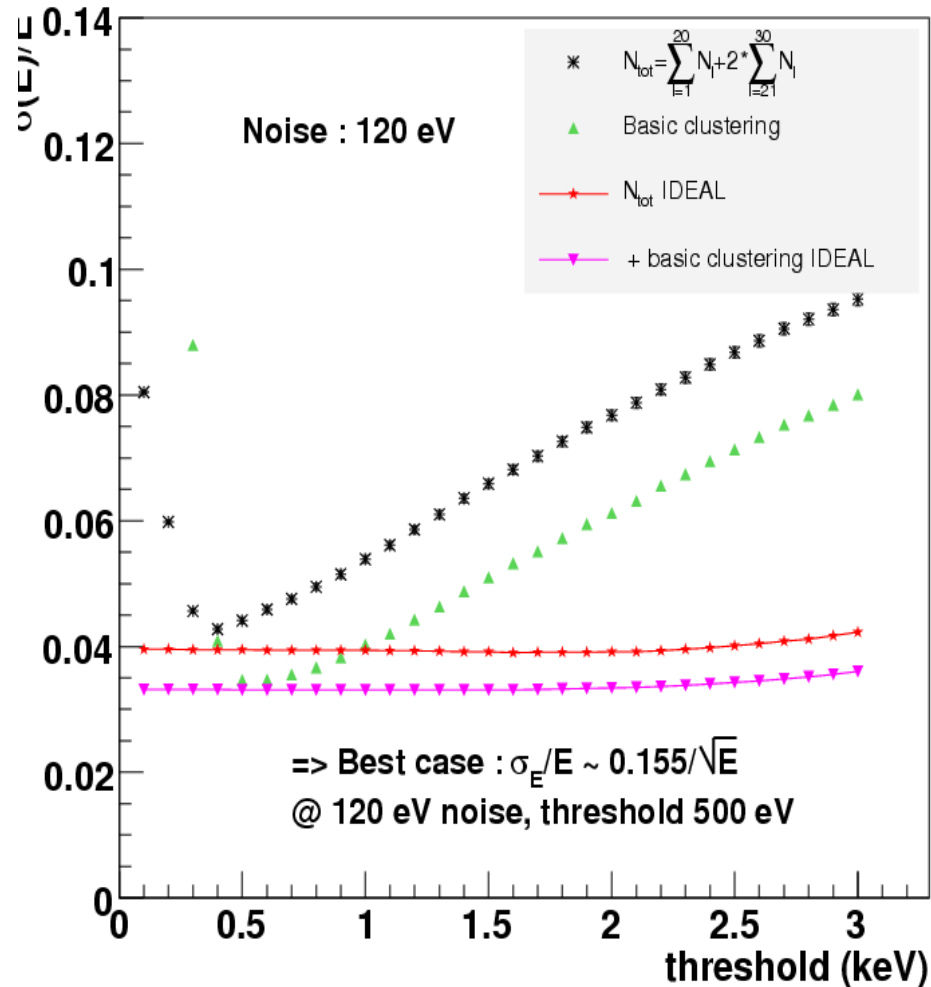
Basic Hit Clustering

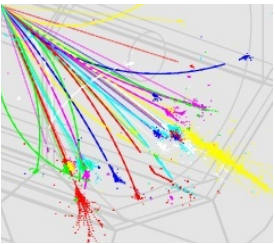


Hit Clustering

- Loop over hits classified by number of neighbors
- Number of neighbors < 8 :
count only 1 (or 2 for last 10 layers) and discard the neighbors
- 8 neighbors AND one of the neighbor has 8 neighbors :
count 2 (or 4) and discard the neighbors

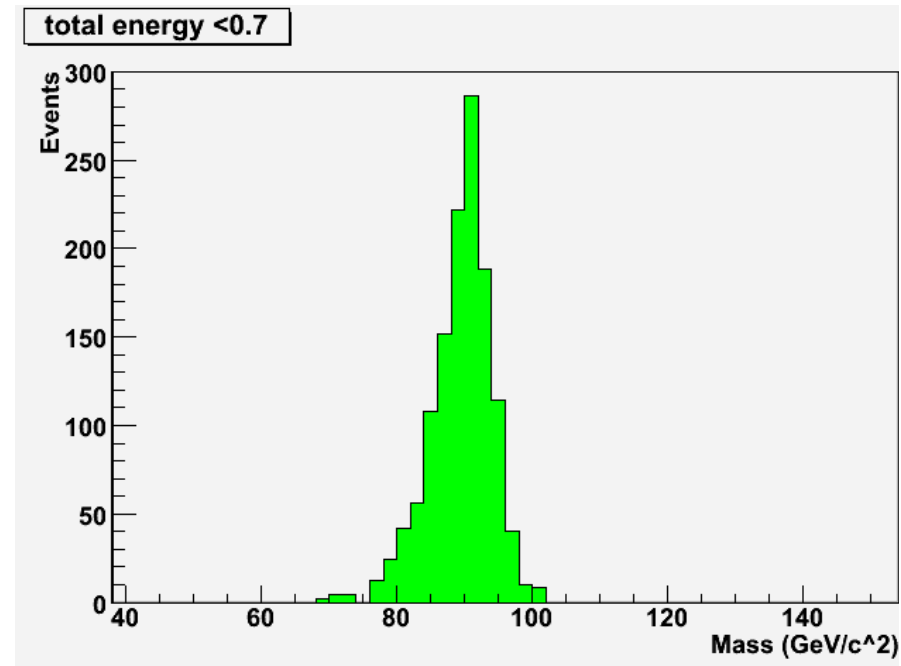
$\sigma(E)/E$ vs Threshold, electron 20 GeV



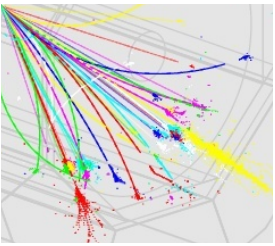


Particle Flow

- Extending **PandoraPFA** to handle Digital ECAL hits
- First **development** version is running
- Lots of things to improve
 - Calibration of MAPS response is critical
 - Optimize clustering for MAPS
 - Particle ID needs modifications
 - Take advantage of MAPS resolution

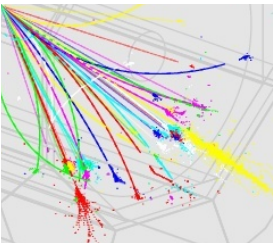


σ_E/\sqrt{E} $0.36+0.01$ for
Z \rightarrow uds at 91 GeV
in the ECAL barrel



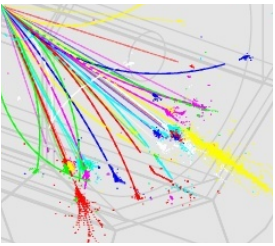
Design Issues

- Pixel parameters
 - Pixel size
 - Number of Diodes / Diode size
- PCB/Readout Chips
- Module structure
- Cooling
- Manufacturing
- Cost



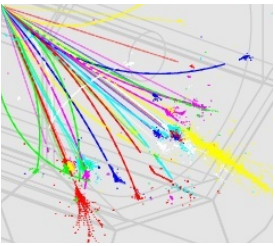
Pixel parameters

- MAPS Pixels improve spatial resolution/granularity by a factor of ~ 1000 compared to analog pad ECAL
- Lower pixel size is set by size of the integrated electronics (lower boundary of $50 \mu\text{m}$)
- Upper bound set by charge collection time/efficiency and multiple hits
- No fixed upper bound, reasonable value is around $100 \mu\text{m}$
- Best performance found with 4 diodes and $1.8 \mu\text{m}$ diode size

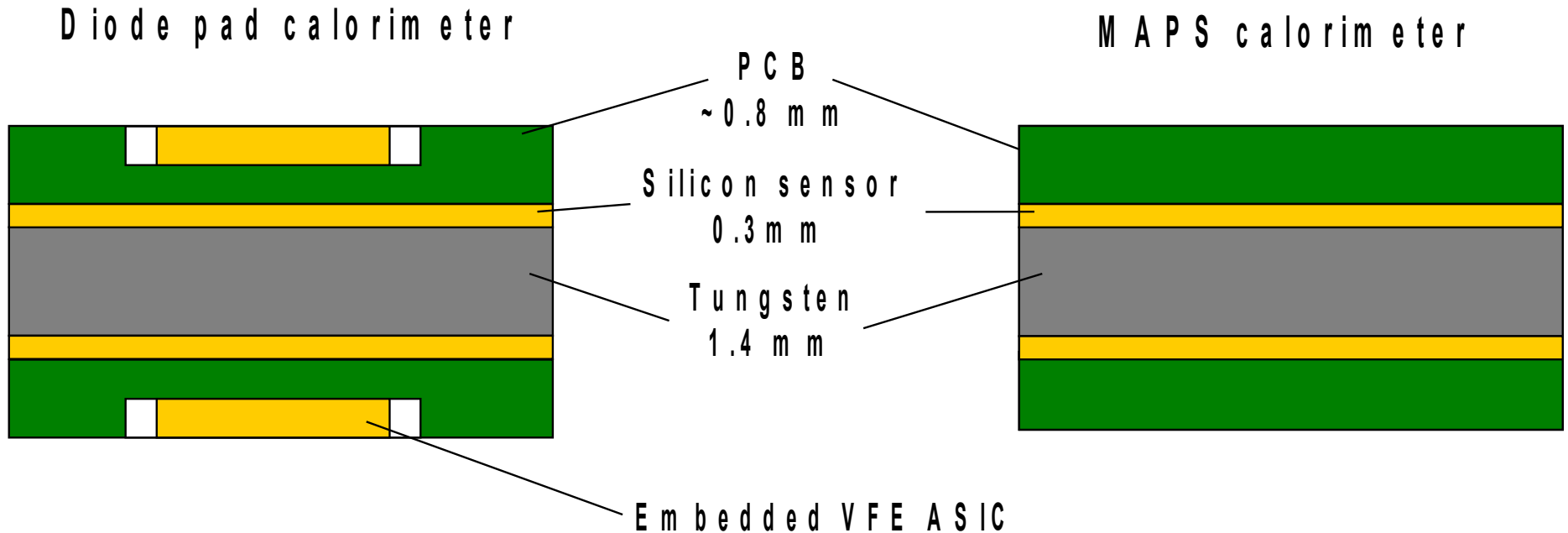


PCB/ Readout Chip

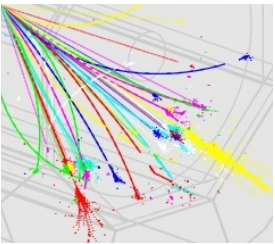
- All the electronics is integrated within the the sensor
- No need for
 - Complicated PCB design
 - Dedicated Readout Chip
- Still needs to provide Power/Clocks/Commands to the MAPS
- Can be done by “Stave Controller” at the end of the Stave



Stave Structure



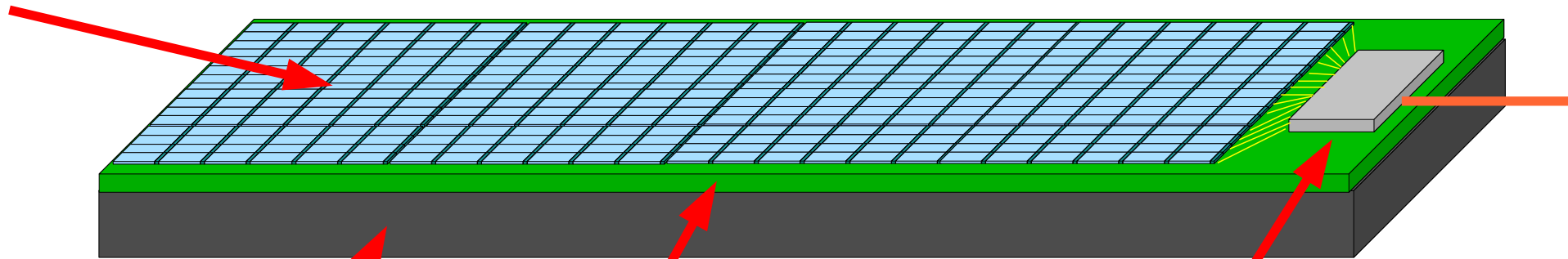
- MAPS can be used as swap-in solution without alterations to the mechanical design (Baseline)
- One can also take further use of MAPS benefits



How it could look like

- Take advantage of MAPS benefits
- Lack of hybrids/ASIC allow less complex/thinner PCB
- Thinner sensors (down to 100 μm)
- Bump-bond MAPS

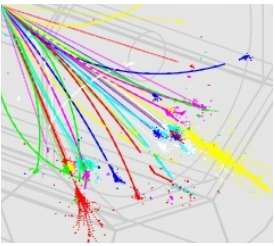
MAPS



Tungsten

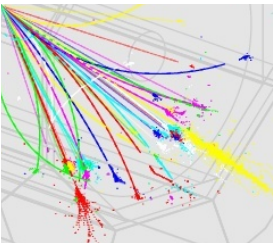
PCB

Stave Controller
with optical link



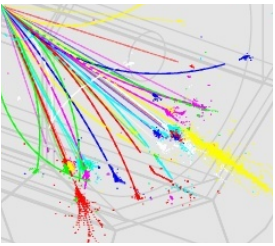
Cooling

- Cooling for the ECAL is a general issue
- Power Savings due to Duty Cycle (1%)
- Target Value for baseline ECAL $4 \mu\text{W}/\text{mm}^2$
- Current Consumption of MAPS ECAL: $60 \mu\text{W}/\text{mm}^2$ depending on pixel technology
- Compared to analog pad ECAL
 - Factor 1000 more Channels
 - Factor 10 more power
- Advantage: Heat load is spread evenly



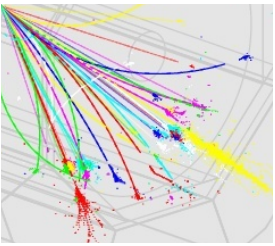
Manufacturing & Costs

- Less complex structure due to lack of VFE ASIC
- Need for large scale process (2000-3000 m²)
- CMOS is an industry standard process
- Many foundries can do it
- CMOS wafers are readily available
- CMOS is ~2 cheaper than “HEP-style” silicon



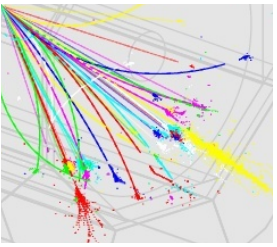
What happens next ?

- Submit Sensor V1.0 Mid April
- Sensor V1.0 due back Mid July
- Improve/enhance GEANT simulation
- Testing Sensor V1.0
- Do physics analyses with a MAPS based ECAL
- Improve sensor simulation with data from V1.0
- Design Sensor V2.0 using all the experience made with V1.0
- Submit Sensor V2.0

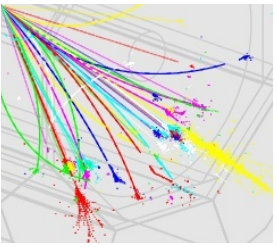


Summary

- MAPS effort is advancing well
- Sensor V1.0 is almost done
- Simulation of MAPS based ECAL made huge progress
- Still quite some challenges ahead
- Interested to work on MAPS ? Contact us !
- Thanks to everyone in the MAPS group for their help in preparing the talk

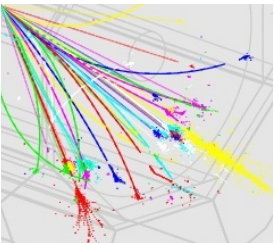


Backup

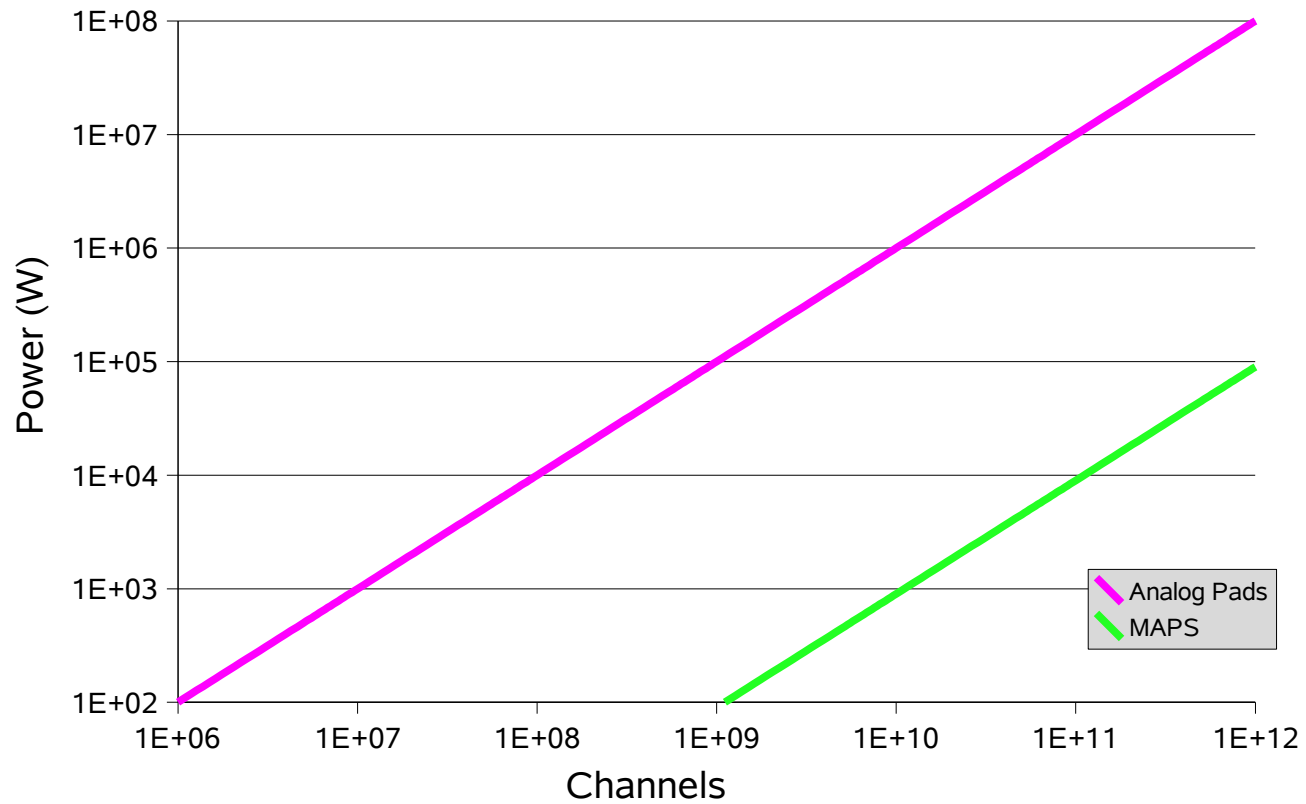


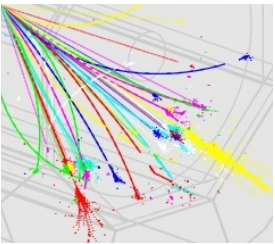
Beam background

- Owen ?



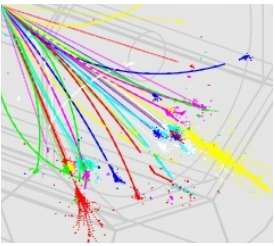
Cooling cont'd





MAPS vs Baseline

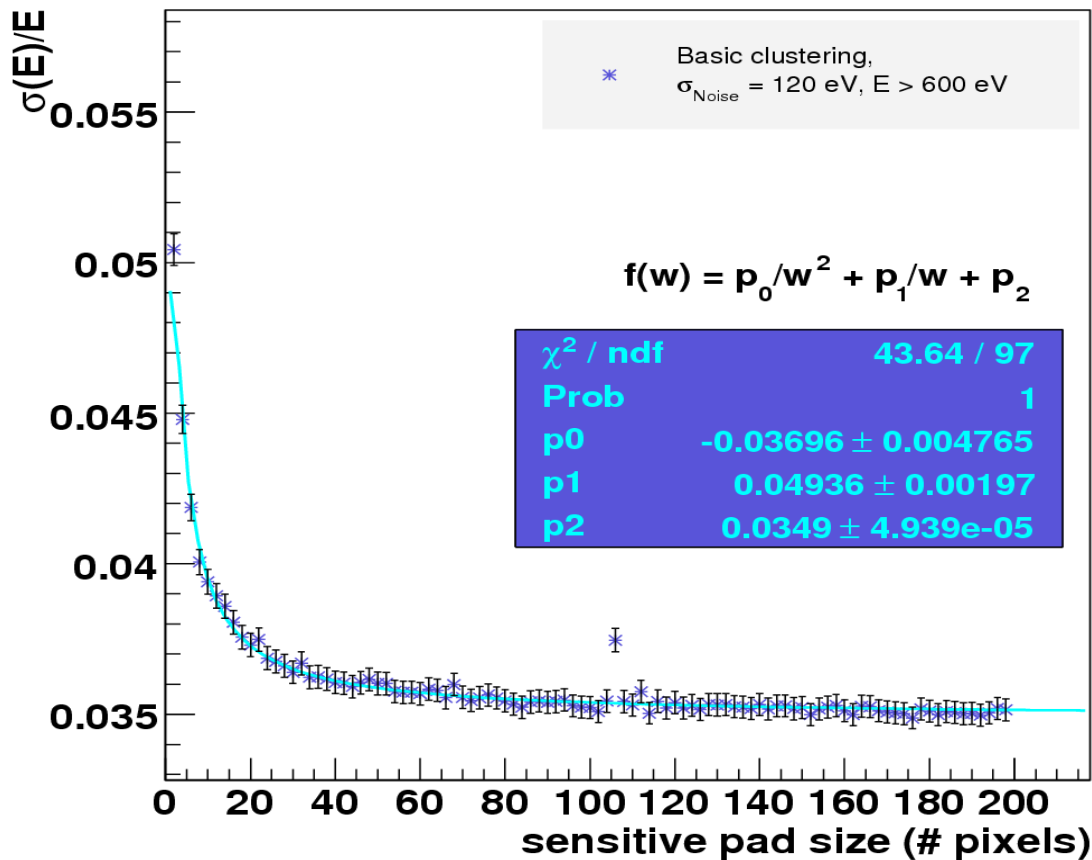
	Baseline	MAPS
Sensor material	high resistivity	CMOS
Pixel size	5 x 5 mm	50 x 50 μm
Readout type	analog	digital
Readout Channels	8×10^7	10^{12}
Power consumption		



Dead area

- We need 5 dead pixels every ~ 42 sensitive pixels (under study) for the pixels logic.

$\sigma(E)/E$ vs sensitive pad size, electron 20 GeV

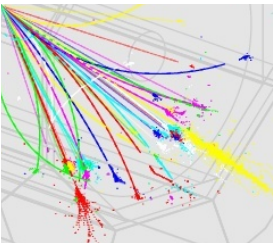


$$\sigma(E)/E = a/\sqrt{E}$$

→ $a = 0.1561$ asymptotical value

→ $a = 0.161$ @ 42 sensitive pixels

→ 3 % increase : we can live with that !!



DAQ data volume

- Physics rate is not the limiting factor
- Beam background and Noise will dominate
- Assuming 2880 bunches and 25 bits per Hit
 - 10^6 Noise hits per bunch
 - $\sim O(1000)$ Hits from Beam background per bunch (estimated)
- Per bunch train
 - ~ 9 Gigabyte Data
 - Readout Required 41 GB/s
 - CDF SVX-II can do 18 GB/s already